



Description

JMT P-channel Enhancement Mode Power MOSFET

Features

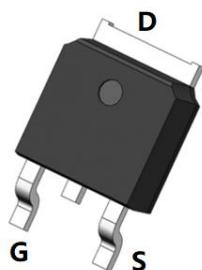
- $V_{DS} = -40V$, $I_D = -40A$
 $R_{DS(ON)} < 13m\Omega$ @ $V_{GS} = -10V$
 $R_{DS(ON)} < 22m\Omega$ @ $V_{GS} = -4.5V$
- Advanced Trench Technology
- Excellent $R_{DS(ON)}$ and Low Gate Charge
- Lead free product is acquired

Application

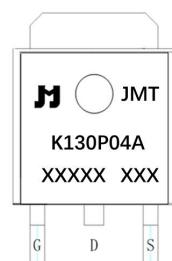
- PWM Applications
- Load Switch
- Power Management



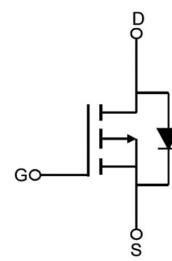
100% UIS TESTED!
100% ΔV_{ds} TESTED!



TO-252-3L(DPAK) top view



Marking and pin Assignment



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
JMTK130P04A	JMTK130P04A	TAPING	TO-252-3L	13inch	2500	25000

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise specified)

Symbol	Parameter		Max.	Units
V_{DSS}	Drain-Source Voltage		-40	V
V_{GSS}	Gate-Source Voltage		± 20	V
I_D	Continuous Drain Current	$T_c = 25^\circ C$	-40	A
		$T_c = 100^\circ C$	-26	A
I_{DM}	Pulsed Drain Current ^{note1}		-160	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}		144	mJ
P_D	Power Dissipation	$T_c = 25^\circ C$	41.6	W
R_{eJC}	Thermal Resistance, Junction to Case		3.6	$^\circ C/W$
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +175	$^\circ C$

**Electrical Characteristics** ($T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristics						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D = -250\mu\text{A}$	-40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -40\text{V}$, $V_{GS}=0\text{V}$	-	-	-1	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS}=0\text{V}$, $V_{GS} = \pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D = -250\mu\text{A}$	-1.0	-1.7	-2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS} = -10\text{V}$, $I_D = -20\text{A}$	-	10	13	$\text{m}\Omega$
		$V_{GS} = -4.5\text{V}$, $I_D = -10\text{A}$	-	15	22	
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = -20\text{V}$, $V_{GS}=0\text{V}$, $f=1.0\text{MHz}$	-	3800	-	pF
C_{oss}	Output Capacitance		-	329	-	pF
C_{rss}	Reverse Transfer Capacitance		-	289	-	pF
Q_g	Total Gate Charge	$V_{DS} = -20\text{V}$, $I_D = -20\text{A}$, $V_{GS} = -10\text{V}$	-	68	-	nC
Q_{gs}	Gate-Source Charge		-	10	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	14	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = -20\text{V}$, $I_D = -20\text{A}$, $V_{GS} = -10\text{V}$, $R_{\text{GEN}} = 2.4\Omega$	-	10	-	ns
t_r	Turn-on Rise Time		-	82	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	93	-	ns
t_f	Turn-off Fall Time		-	74	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_s	Maximum Continuous Drain to Source Diode Forward Current	-	-	-40	A	
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	-160	A	
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}$, $I_s = -30\text{A}$	-	-0.8	-1.2	V
trr	Reverse Recovery Time	$V_{GS}=0\text{V}$, $I_s = -30\text{A}$, $di/dt = 100\text{A}/\mu\text{s}$	-	20	-	ns
Qrr	Reverse Recovery Charge		-	13	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition: $T_J = 25^\circ\text{C}$, $V_{DD} = -20\text{V}$, $V_G = -10\text{V}$, $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = -24\text{A}$ 3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$

Typical Performance Characteristics

Figure 1: Output Characteristics

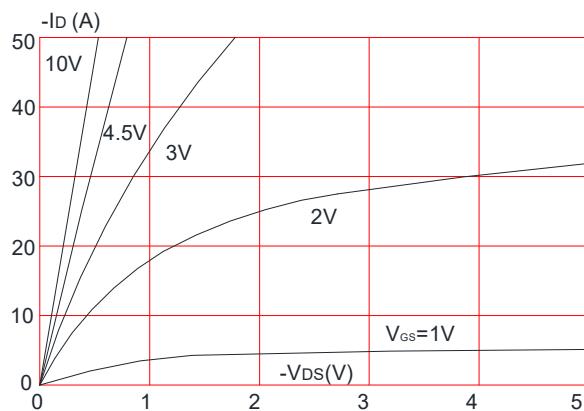


Figure 3: On-resistance vs. Drain Current

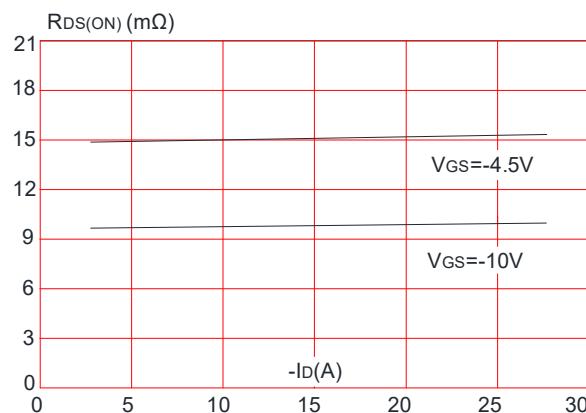


Figure 5: Gate Charge Characteristics

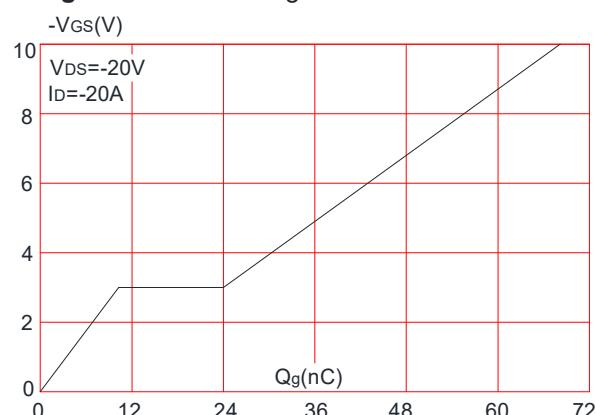


Figure 2: Typical Transfer Characteristics

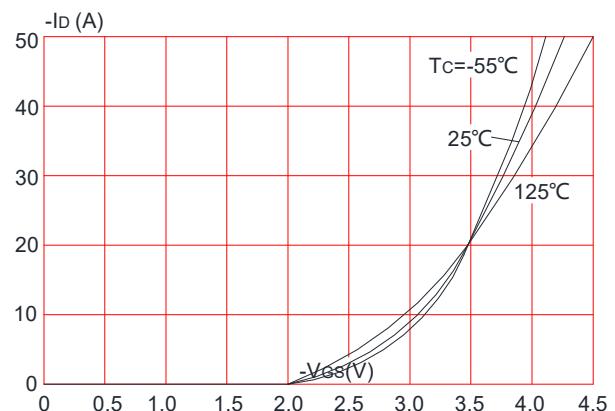


Figure 4: Body Diode Characteristics

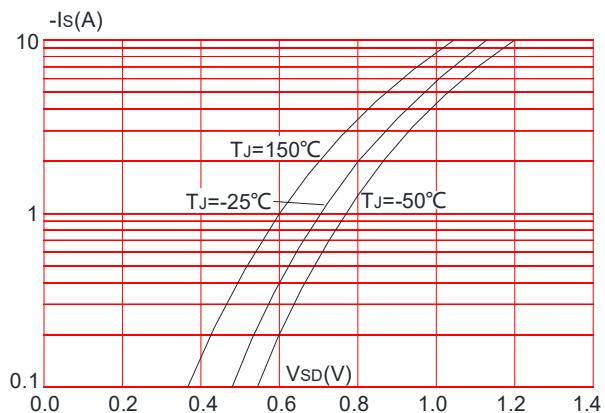


Figure 6: Capacitance Characteristics

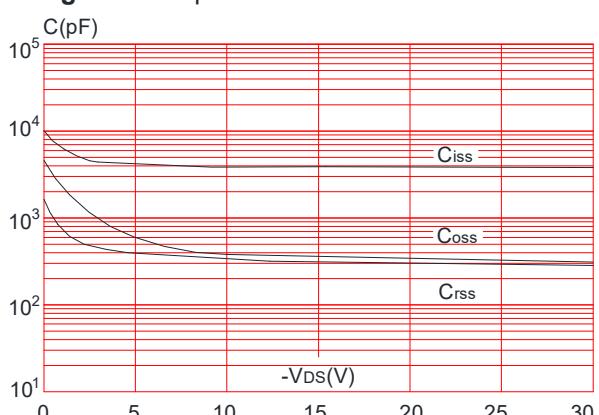


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

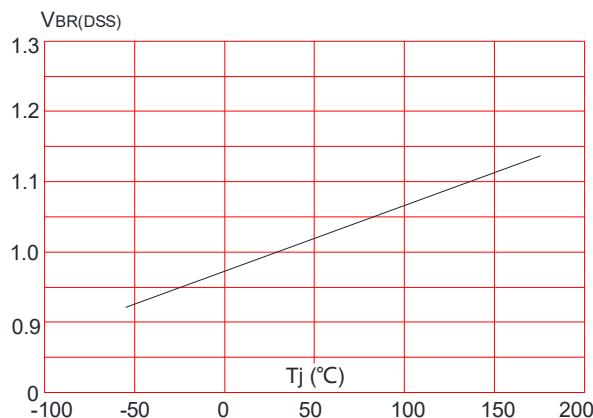


Figure 9: Maximum Safe Operating Area

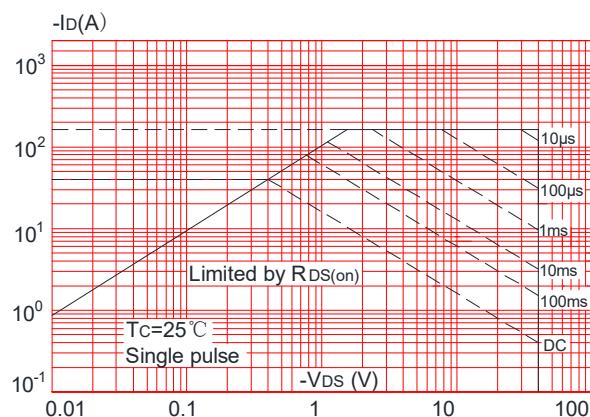


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

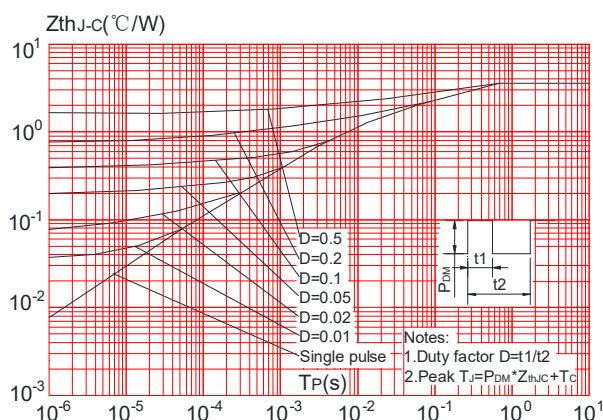


Figure 8: Normalized on Resistance vs. Junction Temperature

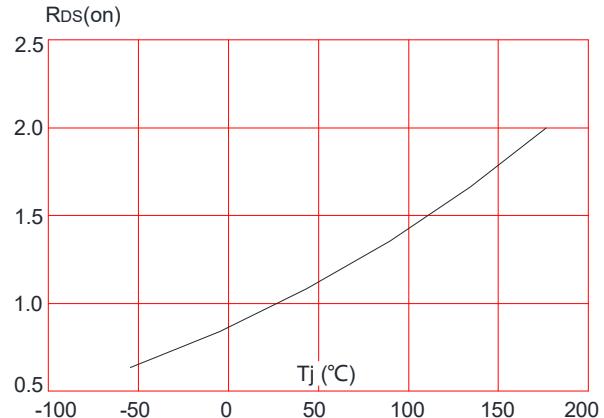
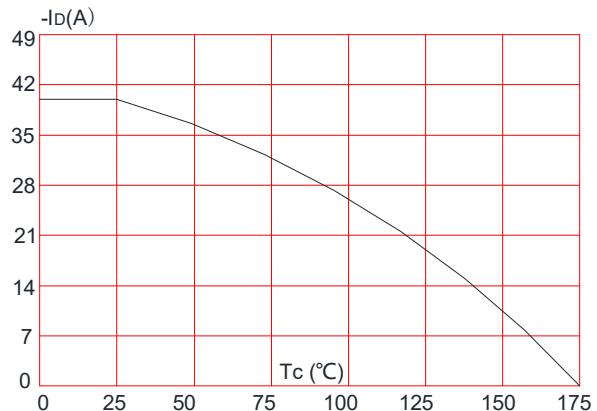
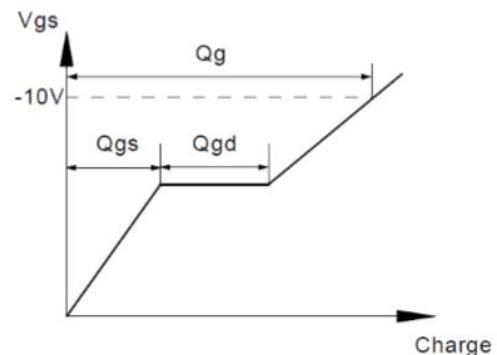
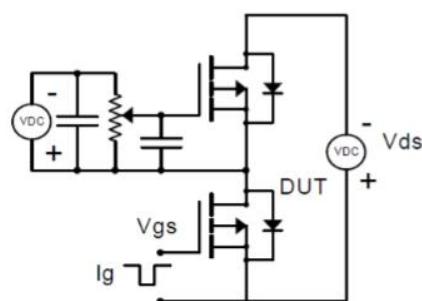


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

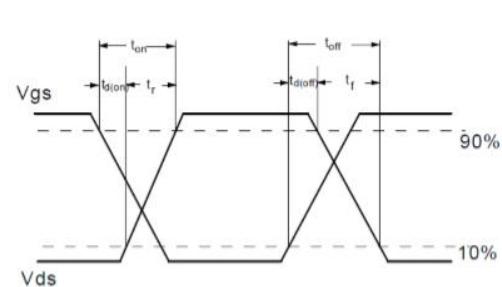
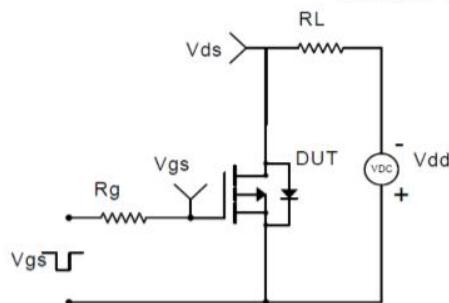


Test Circuit

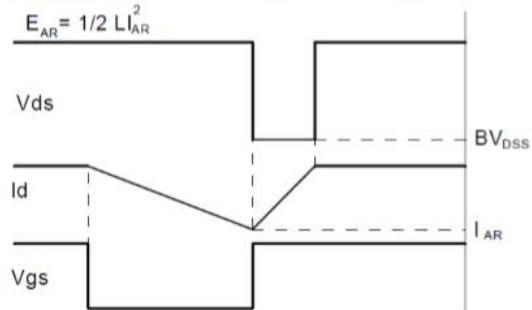
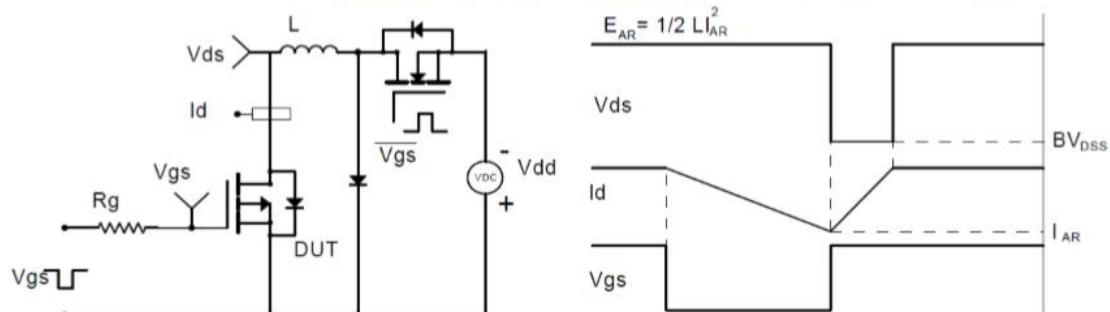
Gate Charge Test Circuit & Waveform



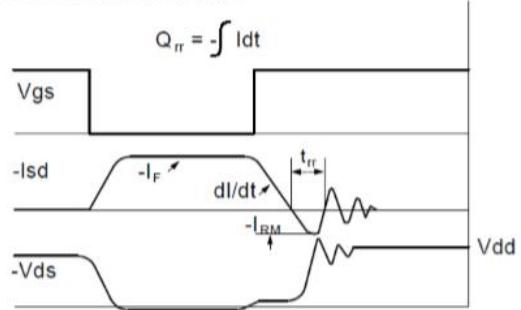
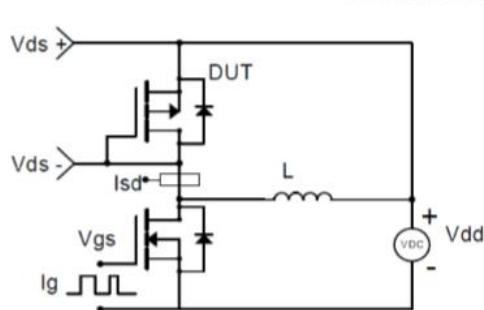
Resistive Switching Test Circuit & Waveforms



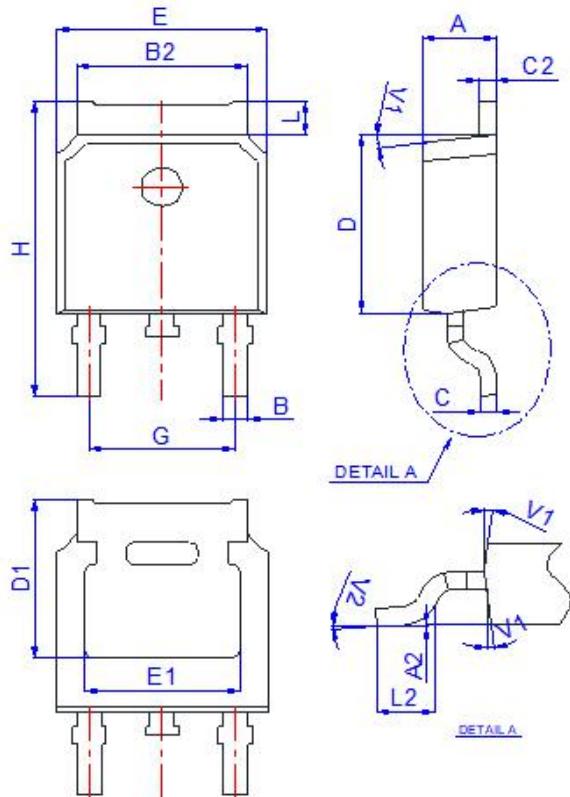
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Mechanical Data-TO-252-3L



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

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